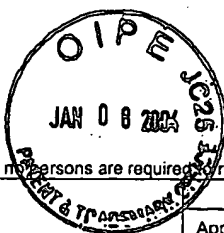


Please type a plus sign (+) inside this box ☐ 0031



PTO/SB/08A (08-00)

Approved for use through 10/31/2002. OMB 0651-

Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it displays a valid OMB control number.

Substitute for Form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Complete If Known	
				Application Number	09/620,943
				Filing Date	07/21/2000
				First Named Inventor	Robert Keller
				Group Art Unit	2882
				Examiner Name	Kao, Chih cheng G
Sheet	1	of	1	Attorney Docket No.	TI-30714

U.S. PATENT DOCUMENTS						
Exam. Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Doc.	Date of Pub. of Cited Doc. (mm-dd-yyyy)	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
AB	AA	5,909,296		Tsacoyeanes	06/01/1999	
	AB					
	AC					
	AD					
	AE					
	AF					
	AG					
	AH					

FOREIGN PATENT DOCUMENTS								
Exam. Initials*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Doc.	Date of Pub. of Cited Doc. (mm-dd-yyyy)	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Office ³	Number ⁴	Kind Code ² (if known)				
AB	BA	EP	0 962 796 A2		Congdon	12/08/1999		
	BB							
	BC							
	BD							
	BE							
	BF							
	BG							
	BH							

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Exam. Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
AB	CA	Tuantranont A et al., "Smart Phase-Only Micromirror Array Fabricated by Standard CMOS Process", Proceedings of the IEEE 13 th Annual International Conference on Micro Electro Mechanical Systems, MEMS 2000. Miyazaki, Japan, Jan. 23-27, 2000, IEEE, U.S. 23 January 2000 (2000-01-23), pages 455-460, XP001045359 ISBN: 0-7803-5274-2.	
	CB		
	CC		
	CD		
	CE		
	CF		
	CG		
	CH		

Examiner Signature	/Agustin Bello/ (01/08/2007)	Date Considered	
--------------------	------------------------------	-----------------	--

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

US and Foreign Patent Documents: ¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

Other Prior Art/Non-Patent Literature Documents: ¹Unique citation designation number. ²Applicant is to place a check mark here if English Translation is attached.